

1222·2022  
**800**  
ANNI



UNIVERSITÀ  
DEGLI STUDI  
DI PADOVA



Istituto Nazionale  
di Fisica Nucleare  
Sezione di Padova

# R&D on novel 4D trackers (3D+timing)

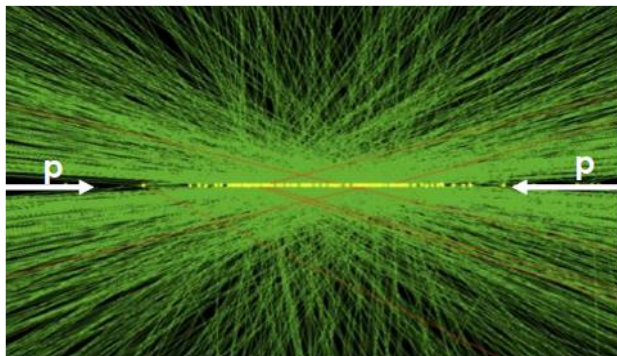
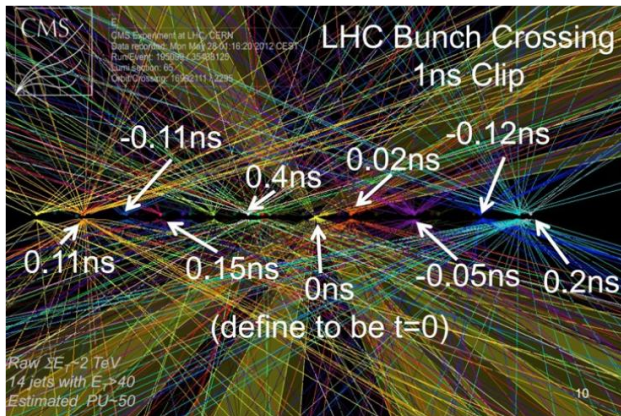
Workshop Laboratori Progetto di Eccellenza

*Serena Mattiazzo*

on behalf of TimeSPOT, APIX and CMS BTL groups

- Scientific motivation for R&D activities on 4D trackers
- Activities at DFA and Padova INFN Section
- Present expertise and equipment
- Future perspectives (within “Progetto Dipartimenti di Eccellenza”)

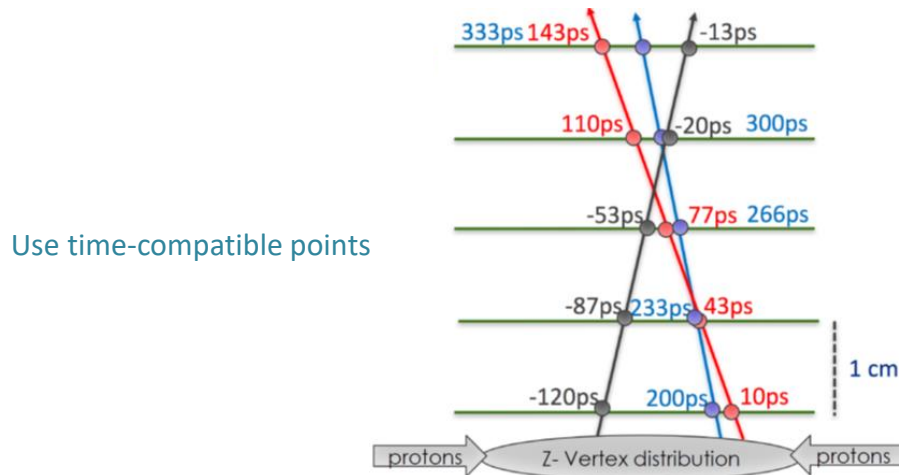
# Timing



- Current situation:  $\sim 50$  vertexes per bunch crossing
- Vertexes **do not overlap** in space  $\rightarrow$  tracking **resolves** the vertexes
- HL-LHC situation:  $\sim 150 - 200$  vertexes per bunch crossing
- Vertexes **overlap** in space  $\rightarrow$  tracking **does not resolve** all vertexes
  - Spread of  $\sim 180$  ps in time collisions  $\rightarrow$  30 ps to reject pile-up of a factor 6 (CMS)
  - with 35 ps time resolution, instances of vertex merging are reduced from 15% in space to 1% in space-time (like CMS LHC conditions)

# Tracking in 4 dimensions

- The inclusion of time in the event information would greatly simplify tracking capability

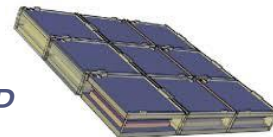


- Timing can be available at different levels of the event reconstruction:
  - Timing in the event reconstruction → Timing layers (time associated to each track)
  - Timing at each point along the track → 4D tracking (3D space tracking + 1D time)

- Detector testing capabilities
- Fast electronics design and production



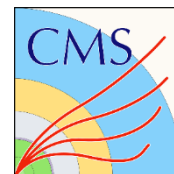
G. Simi, S. Mattiazzo, D. Pantano,  
G. Collazuol



*APIX/ASAP*

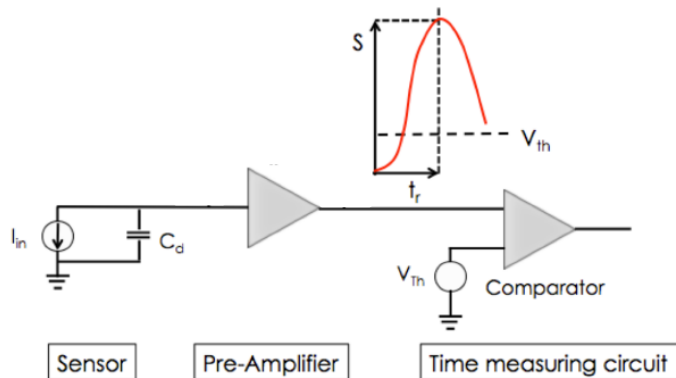
G. Collazuol, L. Silvestrin, S. Mattiazzo

- Mechanics design and development
- Thermal measurements



P. Checchia, U. Dosselli, R. Rossin, S. Ventura,  
R. Isocrate, N. Bez, D. Mazzaro, F. Veronese

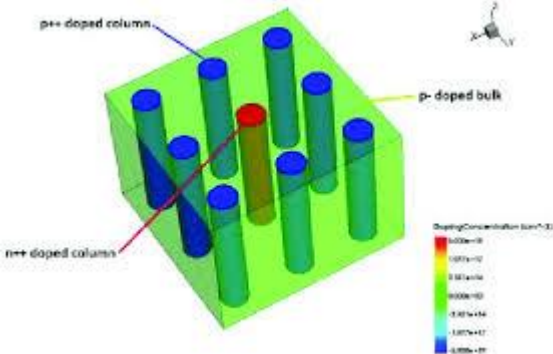
# Silicon pixel detectors for timing: the challenge



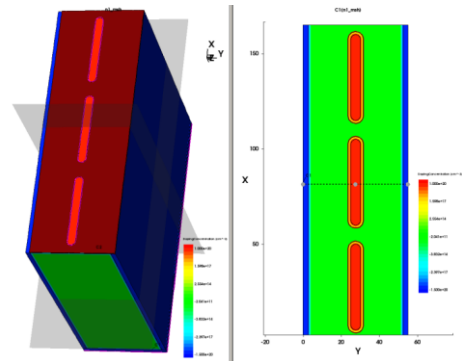
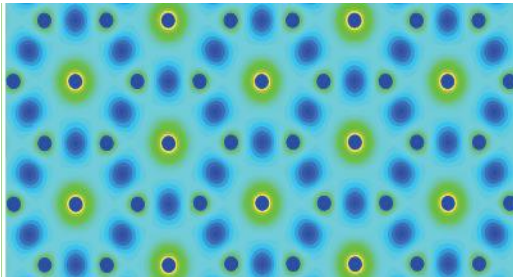
Time is set when the signal crosses the comparator threshold

$$\sigma_t^2 = \underbrace{\sigma_{TimeWalk}^2 + \sigma_{LandauNoise}^2}_{\text{Physics of energy deposition}} + \underbrace{\sigma_{Distortion}^2}_{\text{Sensor Electric Field}} + \underbrace{\sigma_{Jitter}^2}_{\text{Electronics}} + \underbrace{\sigma_{TDC}^2}_{\text{Digitization}}$$

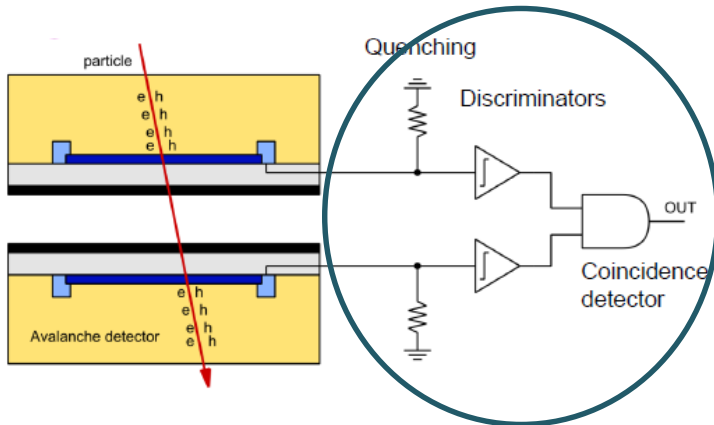
- Uniform electric field  $\Rightarrow$  Sensor R&D
- Fast slew rate  $\sigma_t = \frac{\sigma_V}{\frac{dV}{dt}}$   $\Rightarrow$  Fast electronics development



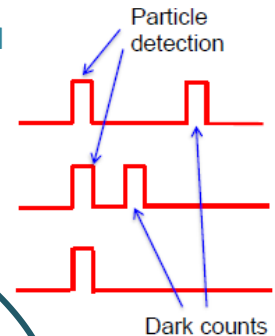
- **Typical column 3D sensors** show very weak spots in electric field which correspond to much slower charge collection times whenever a track crosses the sensor
- Better results can be obtained **with trench electrodes**
  - trench structures increase pixel capacitance,
  - silicon trench geometries have never been produced so far.



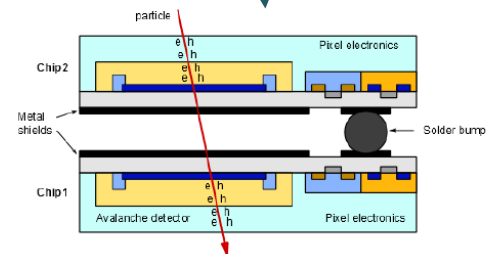
- It is a matrix of **Geiger-mode avalanche detectors**, suitable for particle tracking and imaging, formed by two vertically-aligned pixelated detectors,
- Two vertically-aligned cells are **readout in coincidence** to discriminate between particle-triggered detections and dark counts



In-pixel coincidence:  
integrated  
electronics is needed  
(CMOS avalanche  
detectors)



- reduced material budget
- reduced power consumption
- “simple” electronics → digital readout
- high rate capability
- high timing resolution

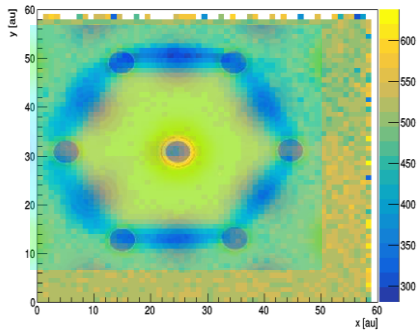




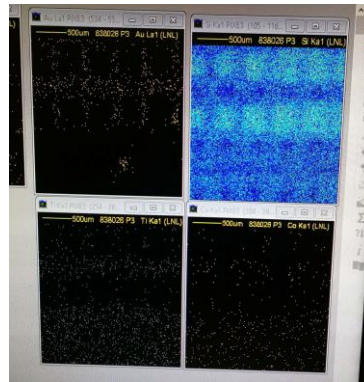
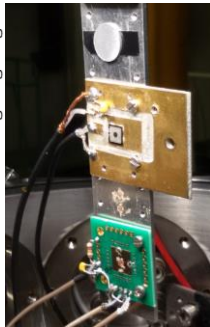
# Pixel mapping with proton microbeam

- Tests both on **APIX** and **TIMESPOT** sensor at the LNL AN2000 proton microbeam
  - 2 MeV protons in a spot of 3-4  $\mu\text{m}$  of diameter.
  - Possibility to rasterize the microbeam over an area of  $5\times 5\text{ mm}^2$  on the focal plane.
  - Can be used both for functionality studies and radiation damage tests.
- **Pixel mapping** to evaluate uniformity of charge collection efficiency (CCE), timing uniformity (3 days of beam time assigned and still to be scheduled)
- **Sample preparation**: scintillating material (p-terphenyl) deposition on sensor surface possible thanks to the colleagues from the Material Physics group (G. Maggioni)

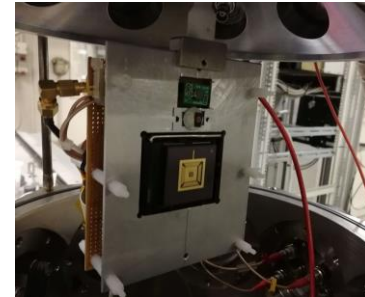
Average pulse height vs position



*Timespot*



*APIX*

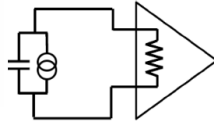


# Presently available instrumentation (1)



Few broadband amplifiers  
(GALI55 from  
Minicircuits, 4 GHz  
current amplifier)

Current Amplifier



Large bandwidth  
oscilloscope  
(model MSO 64  
Tektronix, 4 GHz  
BW)

- IR laser 910 nm and 1064 nm (home-made), ~ ns pulses (too slow for this application)
- Blue laser 409 nm, 40 ps pulses (not optimal wavelength for test on silicon)

Pulse generator HP 8110A (ns pulses,  
again too slow)

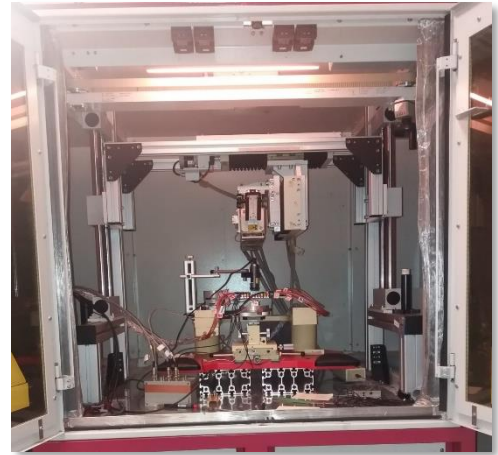


# Presently available instrumentation (2)



Spectrum analyzer  
Semiconductor parameter analyzer  
(HP4156)  
Switching matrix (Keithley 707)

X-ray irradiation facility  
(60kV, 50 mA)



Semi-automatic probe station



Manual probe station

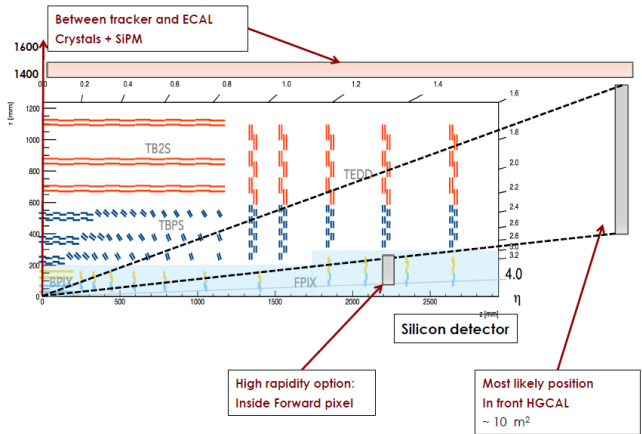


# Wishing list

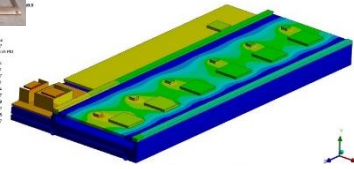
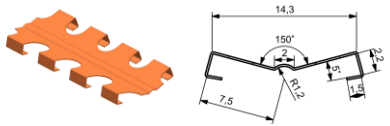
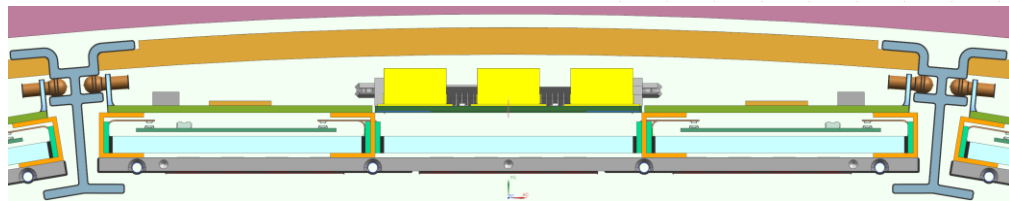
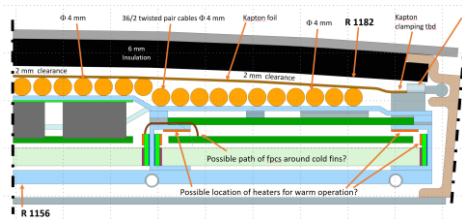
- Complete set of fast current amplifiers (different bandwidths, different gain, etc)
- **Sub ps IR laser** (nJ are sufficient for our purposes), with external trigger, fiber optic coupling and splitting (to shine two different detectors)
- **Optics** for focusing
- **Time-To-Digital (TDC) converters** with ps time resolution (ex SAMPIC)
- Micrometric x-y **motor stages**
- Fast **pulse generator**
- Even faster **oscilloscope (20 GHz)**

**Full chip test  
in lab**

# CMS Barrel Timing Layer (BTL) activities in Padova

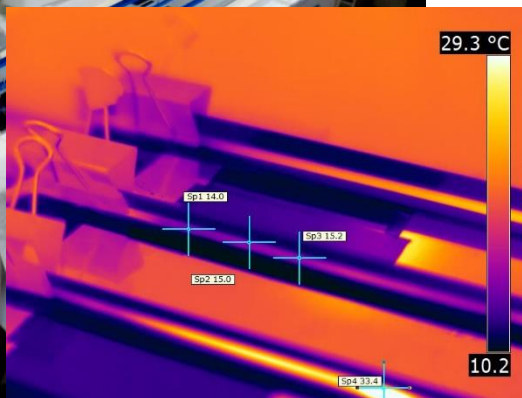
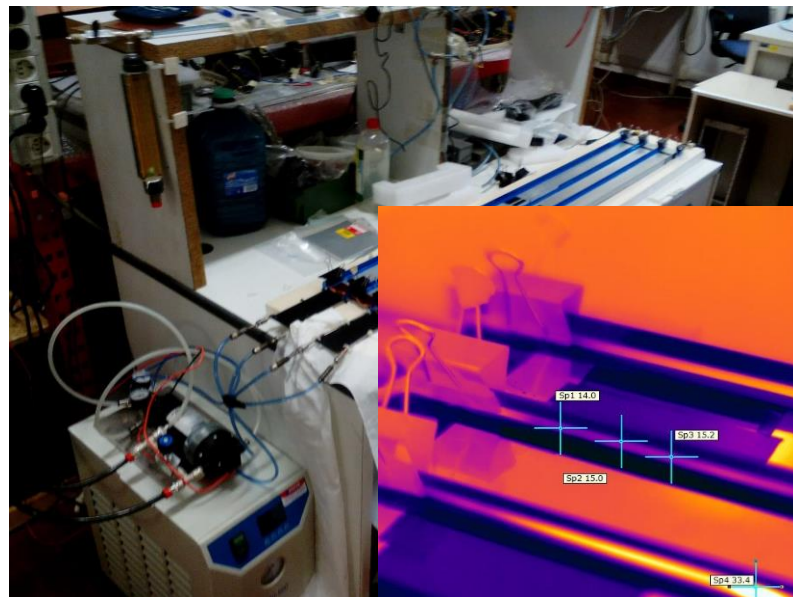


- Tray CAD design and modeling
- FEA thermal simulation
- Tray prototyping of various sizes and solutions
- Assembly and installation study



# BTL measurements in Padova Labs

- Room temperature setup with half tray mockup for  $\Delta T$  measurement between cold plate and SiPMs
- Laboratory fridge acquired to perform temperature measurements up to  $-40^{\circ}\text{C}$  on small ( 1 RU) mockup.
- Model LGT 2325, dimensions: **91 x 114 x 74 cm**



Lab: Lab1 67-68  
Time: 2 years

- **Design and development of analog front-end for silicon pixel sensors**
  - Design of fast, low noise analog front-end electronics (with discrete components, no chip design), good for prototyping and testing of a limited number of channels
  - Design, development and production of DAQ (hardware, firmware, software) for silicon sensors R&D (MAPS, SiPM, etc)
- **Silicon sensor testing capabilities**
  - Electrical characterization of silicon sensors
  - Use of different radiation sources (lasers, calibration sources,) for functional characterization
  - Testing facilities for radiation damage studies and dedicated dosimetry systems (X-ray tube, heavy ions, protons, etc)
  - Facilities for interconnection between (very small) sensors and electronics and characterization test equipment (Al wire bonding, probe stations, probe cards, etc)
- **Mechanical design**
  - Team of designer and engineers, mechanical workshop

# Expertise which we are acquiring

- **Design and development of analog front-end for silicon pixel sensors**
  - Capability to design and assembling electronics working at very high frequencies ( $\approx$  GHz)
  - Capability to work with Time-To-Digital converters (ps time resolution!)
- **Silicon sensor testing capabilities**
  - Capability to build setups using fast lasers

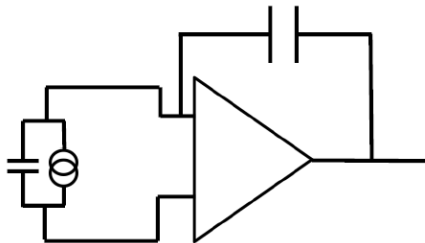


Thanks for attention

backup

# Fast frontend electronics

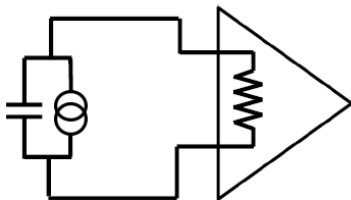
Integrating Amplifier



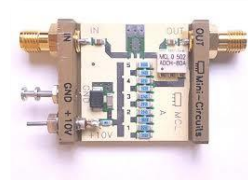
- Slower slew rate
- Lower noise
- Signal smoothing
- Less power



Current Amplifier



- Fast slew rate
- Higher noise
- Sensitive to Landau bumps
- More power



$$\sigma_t = \frac{\sigma_V}{\frac{dV}{dt}}$$



